## MATH 450: Mathematical statistics

November 5th, 2019

Lecture 20: P-values

# Overview

Week 2 · · · · •	Chapter 6: Statistics and Sampling Distributions				
Week 4 · · · · ·	Chapter 7: Point Estimation				
Week 7 · · · ·	Chapter 8: Confidence Intervals				
Week 10 · · · ·	Chapter 9: Tests of Hypotheses				
Week 12 · · · ·	Chapter 10: Two-sample testing				
Week 14 · · · · ·	Regression				

# Key steps in statistical inference

- Understand statistical models [Chapter 6]
- Come up with reasonable estimates of the parameters of interest [Chapter 7]
- Quantify the confidence with the estimates [Chapter 8]
- Testing with the parameters of interest [Chapter 9]

#### Contexts

- The central mega-example: population mean  $\mu$
- Difference between two population means

# Chapter 9: Overview

- 9.1 Hypotheses and test procedures
  - test procedures
  - errors in hypothesis testing
  - significance level
- 9.2 Tests about a population mean
  - ullet normal population with known  $\sigma$
  - large-sample tests
  - ullet a normal population with unknown  $\sigma$
- 9.4 P-values

# Hypothesis testing for one parameter

- Identify the parameter of interest
- 2 Determine the null value and state the null hypothesis
- 3 State the appropriate alternative hypothesis
- Give the formula for the test statistic
- lacktriangle State the rejection region for the selected significance level lpha
- Ompute statistic value from data
- Decide whether  $H_0$  should be rejected and state this conclusion in the problem context

# Test about a population mean

Null hypothesis

$$H_0: \mu = \mu_0$$

- The alternative hypothesis will be either:
  - $H_a: \mu > \mu_0$
  - $H_a: \mu < \mu_0$
  - $H_a: \mu \neq \mu_0$

# Normal population with known $\sigma$

Null hypothesis:  $\mu = \mu_0$ Test statistic:

$$Z = \frac{\bar{X} - \mu_0}{\sigma / \sqrt{n}}$$

. .

#### Alternative Hypothesis

$$H_{a}$$
:  $\mu > \mu_{0}$   
 $H_{a}$ :  $\mu < \mu_{0}$ 

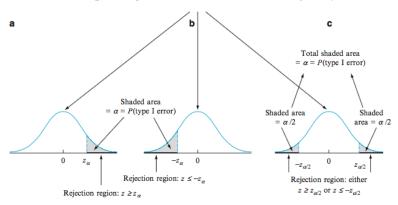
$$H_a$$
:  $\mu \neq \mu_0$ 

### Rejection Region for Level $\alpha$ Test

$$z \ge z_{\alpha}$$
 (upper-tailed test)  
 $z \le -z_{\alpha}$  (lower-tailed test)  
either  $z \ge z_{\alpha/2}$  or  $z \le -z_{\alpha/2}$  (two-tailed test)

## General rule

z curve (probability distribution of test statistic Z when  $H_0$  is true)



# Example

### Problem

A manufacturer of sprinkler systems used for fire protection in office buildings claims that the true average system-activation temperature is  $130^{\circ}F$ . A sample of n=9 systems, when tested, yields a sample average activation temperature of  $131.08^{\circ}F$ .

If the distribution of activation times is normal with standard deviation 1.5°F, does the data contradict the manufacturer's claim at significance level  $\alpha=0.01$ ?

## Solution

- $\bullet$  Parameter of interest:  $\mu = {\rm true}$  average activation temperature
- Hypotheses

$$H_0: \mu = 130$$
  
 $H_a: \mu \neq 130$ 

Test statistic:

$$z = \frac{\bar{x} - 130}{1.5/\sqrt{n}}$$

- Rejection region: either  $z \le -z_{0.005}$  or  $z \ge z_{0.005} = 2.58$
- Substituting  $\bar{x} = 131.08$ ,  $n = 25 \rightarrow z = 2.16$ .
- Note that -2.58 < 2.16 < 2.58. We fail to reject  $H_0$  at significance level 0.01.
- The data does not give strong support to the claim that the true average differs from the design value.

Large-sample tests

# Large-sample tests

Null hypothesis:  $\mu = \mu_0$ Test statistic:

$$Z = \frac{\bar{X} - \mu_0}{S/\sqrt{n}}$$

### **Alternative Hypothesis**

### Rejection Region for Level α Test

$$H_{a}$$
:  $\mu > \mu_{0}$   
 $H_{a}$ :  $\mu < \mu_{0}$   
 $H_{a}$ :  $\mu \neq \mu_{0}$ 

$$z \ge z_{\alpha}$$
 (upper-tailed test)  
 $z \le -z_{\alpha}$  (lower-tailed test)  
either  $z \ge z_{\alpha/2}$  or  $z \le -z_{\alpha/2}$  (two-tailed test)

[Does not need the normal assumption]

Test about a normal population with unknown  $\boldsymbol{\sigma}$ 

Null hypothesis: 
$$H_0$$
:  $\mu = \mu_0$   
Test statistic value:  $t = \frac{\overline{x} - \mu_0}{s/\sqrt{n}}$ 

#### Alternative Hypothesis

## Rejection Region for a Level $\alpha$ Test

$$H_a$$
:  $\mu > \mu_0$   $t \ge t_{\alpha,n-1}$  (upper-tailed)  
 $H_a$ :  $\mu < \mu_0$   $t \le -t_{\alpha,n-1}$  (lower-tailed)  
 $H_a$ :  $\mu \ne \mu_0$  either  $t \ge t_{\alpha/2,n-1}$  or  $t \le -t_{\alpha/2,n-1}$  (two-tailed)

[Require normal assumption]

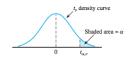
# Example

#### Problem

The amount of shaft wear (.0001 in.) after a fixed mileage was determined for each of n=8 internal combustion engines having copper lead as a bearing material, resulting in  $\bar{x}=3.72$  and s=1.25.

Assuming that the distribution of shaft wear is normal with mean  $\mu$ , use the t-test at level 0.05 to test  $H_0$ :  $\mu=3.5$  versus  $H_a$ :  $\mu>3.5$ .

 Table A.5
 Critical Values for t Distributions



	α								
ν	.10	.05	.025	.01	.005	.001	.0005		
1	3.078	6.314	12.706	31.821	63.657	318.31	636.62		
2	1.886	2.920	4.303	6.965	9.925	22.326	31.598		
3	1.638	2.353	3.182	4.541	5.841	10.213	12.924		
4	1.533	2.132	2.776	3.747	4.604	7.173	8.610		
5	1.476	2.015	2.571	3.365	4.032	5.893	6.869		
6	1.440	1.943	2.447	3.143	3.707	5.208	5.959		
7	1.415	1.895	2.365	2.998	3.499	4.785	5.408		
8	1.397	1.860	2.306	2.896	3.355	4.501	5.041		
9	1.383	1.833	2.262	2.821	3.250	4.297	4.781		
10	1.372	1.812	2.228	2.764	3.169	4.144	4.587		
11	1.363	1.796	2.201	2.718	3.106	4.025	4.437		
12	1.356	1.782	2.179	2.681	3.055	3.930	4.318		
13	1.350	1.771	2.160	2.650	3.012	3.852	4.221		
14	1.345	1.761	2.145	2.624	2.977	3.787	4.140		
15	1.341	1.753	2.131	2.602	2.947	3.733	4.073		
16	1.337	1.746	2.120	2.583	2.921	3.686	4.015		
17	1.333	1.740	2.110	2.567	2.898	3.646	3.965		
18	1.330	1.734	2.101	2.552	2.878	3.610	3.922		
19	1.328	1.729	2.093	2.539	2.861	3.579	3.883		
20	1.325	1.725	2.086	2.528	2.845	3.552	3.850		
21	1.323	1.721	2.080	2.518	2.831	3.527	3.819		
22	1.321	1.717	2.074	2.508	2.819	3.505	3.792		
23	1.319	1.714	2.069	2.500	2.807	3.485	3.767		
24	1.318	1.711	2.064	2.492	2.797	3.467	3.745		

### **Practice**

#### Problem

The standard thickness for silicon wafers used in a certain type of integrated circuit is 245  $\mu$ m. A sample of 50 wafers is obtained and the thickness of each one is determined, resulting in a sample mean thickness of 246.18  $\mu$ m and a sample standard deviation of 3.60  $\mu$ m.

Does this data suggest that true average wafer thickness is larger than the target value? Carry out a test of significance at level .05.

Type II error and sample size determination

# Hypothesis testing for one parameter

- Identify the parameter of interest
- 2 Determine the null value and state the null hypothesis
- State the appropriate alternative hypothesis
- Give the formula for the test statistic
- lacktriangle State the rejection region for the selected significance level lpha
- Ompute statistic value from data
- Decide whether  $H_0$  should be rejected and state this conclusion in the problem context

# Type II error and sample size determination

- A level  $\alpha$  test is a test with  $P[\text{type I error}] = \alpha$
- Question: given  $\alpha$  and n, can we compute  $\beta$  (the probabilities of type II error)?
- This is a very difficult question.
- We have a solution for the cases when: the distribution is normal and  $\sigma$  is known

# Practice problem

#### Problem

The drying time of a certain type of paint under specified test conditions is known to be normally distributed with standard deviation 9 min. Assuming that we are testing

$$H_0: \mu = 75$$

$$H_a: \mu < 75$$

from a dataset with n = 25.

- What is the rejection region of the test with significance level  $\alpha = 0.05$ .
- What is  $\beta(70)$  in this case?

### General cases

Test of hypotheses:

$$H_0: \mu = \mu_0$$
  
 $H_a: \mu < \mu_0$ 

- Rejection region:  $z \le -z_{\alpha}$
- This is equivalent to  $\bar{x} \leq \mu_0 z_\alpha \sigma / \sqrt{n}$
- Let  $\mu' < \mu_0$

$$\beta(\mu') = P[\text{Type II error when } \mu = \mu']$$

$$= P[H_0 \text{ is not rejected while it is false because } \mu = \mu']$$

$$= P[\bar{X} > \mu_0 - z_\alpha \sigma / \sqrt{n} \text{ while } \mu = \mu']$$

$$= P\left[\frac{\bar{X} - \mu'}{\sigma / \sqrt{n}} > \frac{\mu_0 - \mu'}{\sigma / \sqrt{n}} - z_\alpha \text{ while } \mu = \mu'\right]$$

$$= 1 - \Phi\left(\frac{\mu_0 - \mu'}{\sigma / \sqrt{n}} - z_\alpha\right)$$

## Remark

• For  $\mu' < \mu_0$ :

$$eta(\mu') = 1 - \Phi\left(rac{\mu_0 - \mu'}{\sigma/\sqrt{n}} - z_lpha
ight)$$

• If  $n, \mu', \mu_0, \sigma$  is fixed, then

$$\beta(\mu') \text{ is small}$$

$$\leftrightarrow \Phi\left(\frac{\mu_0 - \mu'}{\sigma/\sqrt{n}} - z_\alpha\right) \text{ is large}$$

$$\leftrightarrow \frac{\mu_0 - \mu'}{\sigma/\sqrt{n}} - z_\alpha \text{ is large}$$

$$\leftrightarrow \alpha \text{ is large}$$

# $\alpha - \beta$ compromise

### Proposition

Suppose an experiment and a sample size are fixed and a test statistic is chosen. Then decreasing the size of the rejection region to obtain a smaller value of  $\alpha$  results in a larger value of  $\beta$  for any particular parameter value consistent with  $H_a$ .

## General formulas

#### Alternative Hypothesis

Type II Error Probability  $\beta(\mu')$  for a Level  $\alpha$  Test

$$\begin{split} H_{a}\!\!: & \mu > \mu_{0} \\ H_{a}\!\!: & \mu < \mu_{0} \\ H_{a}\!\!: & \mu < \mu_{0} \\ \end{split} \qquad \begin{aligned} & \Phi\!\left(z_{x} + \frac{\mu_{0} - \mu'}{\sigma/\sqrt{n}}\right) \\ & 1 - \Phi\!\left(-z_{x} + \frac{\mu_{0} - \mu'}{\sigma/\sqrt{n}}\right) \\ & \Phi\!\left(z_{x/2} + \frac{\mu_{0} - \mu'}{\sigma/\sqrt{n}}\right) - \Phi\!\left(-z_{x/2} + \frac{\mu_{0} - \mu'}{\sigma/\sqrt{n}}\right) \end{aligned}$$

where  $\Phi(z)$  = the standard normal cdf.

The sample size n for which a level  $\alpha$  test also has  $\beta(\mu') = \beta$  at the alternative value  $\mu'$  is

$$n = \begin{cases} \left[ \frac{\sigma(z_{\alpha} + z_{\beta})}{\mu_{0} - \mu'} \right]^{2} & \text{for a one - tailed} \\ \left[ \frac{\sigma(z_{\alpha/2} + z_{\beta})}{\mu_{0} - \mu'} \right]^{2} & \text{for a two - tailed test} \\ \left[ \frac{\sigma(z_{\alpha/2} + z_{\beta})}{\mu_{0} - \mu'} \right]^{2} & \text{for a two - tailed test} \end{cases}$$

### P-values

## Remarks

- The common approach in statistical testing is:
  - lacktriangle specifying significance level lpha
  - $\bigcirc$  reject/not reject  $H_0$  based on evidence
- Weaknesses of this approach:
  - it says nothing about whether the computed value of the test statistic just barely fell into the rejection region or whether it exceeded the critical value by a large amount
  - each individual may select their own significance level for their presentation
- We also want to include some objective quantity that describes how strong the rejection is → P-value

# Practice problem

#### Problem

Suppose  $\mu$  was the true average nicotine content of brand of cigarettes. We want to test:

$$H_0$$
:  $\mu = 1.5$ 

$$H_{a}$$
 :  $\mu > 1.5$ 

Suppose that n=64 and  $z=\frac{\bar{x}-1.5}{s/\sqrt{n}}=2.1$ . Will we reject  $H_0$  if the significance level is

- (a)  $\alpha = 0.05$
- (b)  $\alpha = 0.025$
- (c)  $\alpha = 0.01$
- (d)  $\alpha = 0.005$

### P-value

Level of Significance $\alpha$	Rejection Region	Conclusion
.05	z ≥ 1.645	Reject H <sub>0</sub>
.025	$z \ge 1.96$	Reject $H_0$
.01	$z \ge 2.33$	Do not reject $H_0$
.005	$z \ge 2.58$	Do not reject $H_0$

Question: What is the smallest value of  $\alpha$  for which  $H_0$  is rejected.

### P-value

#### DEFINITION

The **P-value** (or observed significance level) is the smallest level of significance at which  $H_0$  would be rejected when a specified test procedure is used on a given data set. Once the P-value has been determined, the conclusion at any particular level  $\alpha$  results from comparing the P-value to  $\alpha$ :

- 1. P-value  $\leq \alpha \Rightarrow$  reject  $H_0$  at level  $\alpha$ .
- **2.** P-value  $> \alpha \Rightarrow$  do not reject  $H_0$  at level  $\alpha$ .

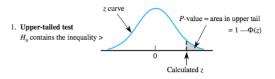
# Testing by P-value method

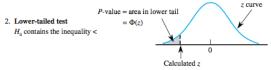
DECISION
RULE BASED
ON THE
P-VALUE

Select a significance level  $\alpha$  (as before, the desired type I error probability). Then reject  $H_0$  if P-value  $\leq \alpha$ ; do not reject  $H_0$  if P-value  $> \alpha$ 

Remark: the smaller the P-value, the more evidence there is in the sample data against the null hypothesis and for the alternative hypothesis.

## P-values for z-tests





3. Two-tailed test  $H_a$  contains the inequality  $\neq$ 

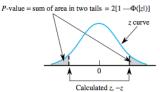


Figure 9.7 Determination of the P-value for a z test

# Practice problem

#### Problem

The target thickness for silicon wafers used in a certain type of integrated circuit is 245  $\mu$ m. A sample of 50 wafers is obtained and the thickness of each one is determined, resulting in a sample mean thickness of 246.18  $\mu$ m and a sample standard deviation of 3.60  $\mu$ m.

At confidence level  $\alpha = 0.01$ , does this data suggest that true average wafer thickness is something other than the target value?

									X-7	
z	.00	.01	.02	.03	.04	.05	.06	.07	.08	.09
0.0	.5000	.5040	.5080	.5120	.5160	.5199	.5239	.5279	.5319	.5359
0.1	.5398	.5438	.5478	.5517	.5557	.5596	.5636	.5675	.5714	.5753
0.2	.5793	.5832	.5871	.5910	.5948	.5987	.6026	.6064	.6103	.6141
0.3	.6179	.6217	.6255	.6293	.6331	.6368	.6406	.6443	.6480	.6517
0.4	.6554	.6591	.6628	.6664	.6700	.6736	.6772	.6808	.6844	.6879
0.5	.6915	.6950	.6985	.7019	.7054	.7088	.7123	.7157	.7190	.7224
0.6	.7257	.7291	.7324	.7357	.7389	.7422	.7454	.7486	.7517	.7549
0.7	.7580	.7611	.7642	.7673	.7704	.7734	.7764	.7794	.7823	.7852
0.8	.7881	.7910	.7939	.7967	.7995	.8023	.8051	.8078	.8106	.8133
0.9	.8159	.8186	.8212	.8238	.8264	.8289	.8315	.8340	.8365	.8389
1.0	.8413	.8438	.8461	.8485	.8508	.8531	.8554	.8577	.8599	.8621
1.1	.8643	.8665	.8686	.8708	.8729	.8749	.8770	.8790	.8810	.8830
1.2	.8849	.8869	.8888	.8907	.8925	.8944	.8962	.8980	.8997	.9015
1.3	.9032	.9049	.9066	.9082	.9099	.9115	.9131	.9147	.9162	.9177
1.4	.9192	.9207	.9222	.9236	.9251	.9265	.9278	.9292	.9306	.9319
1.5	.9332	.9345	.9357	.9370	.9382	.9394	.9406	.9418	.9429	.9441
1.6	.9452	.9463	.9474	.9484	.9495	.9505	.9515	.9525	.9535	.9545
1.7	.9554	.9564	.9573	.9582	.9591	.9599	.9608	.9616	.9625	.9633
1.8	.9641	.9649	.9656	.9664	.9671	.9678	.9686	.9693	.9699	.9706
1.9	.9713	.9719	.9726	.9732	.9738	.9744	.9750	.9756	.9761	.9767
2.0	.9772	.9778	.9783	.9788	.9793	.9798	.9803	.9808	.9812	.9817
2.1	.9821	.9826	.9830	.9834	.9838	.9842	.9846	.9850	.9854	.9857
2.2	.9861	.9864	.9868	.9871	.9875	.9878	.9881	.9884	.9887	.9890
2.3	.9893	.9896	.9898	.9901	.9904	.9906	.9909	.9911	.9913	.9916
2.4	.9918	.9920	.9922	.9925	.9927	.9929	.9931	.9932	.9934	.9936
2.5	.9938	.9940	.9941	.9943	.9945	.9946	.9948	.9949	.9951	.9952
2.6	.9953	.9955	.9956	.9957	.9959	.9960	.9961	.9962	.9963	.9964
2.7	.9965	.9966	.9967	.9968	.9969	.9970	.9971	.9972	.9973	.9974
2.8	.9974	.9975	.9976	.9977	.9977	.9978	.9979	.9979	.9980	.9981
2.9	.9981	.9982	.9982	.9983	.9984	.9984	.9985	.9985	.9986	.9986
3.0	.9987	.9987	.9987	.9988	.9988	.9989	.9989	.9989	.9990	.9990
3.1	.9990	.9991	.9991	.9991	.9992	.9992	.9992	.9992	.9993	.9993
3.2	.9993	.9993	.9994	.9994	.9994	.9994	.9994	.9995	.9995	.9995
3.3	.9995	.9995	.9995	.9996	.9996	.9996	.9996	.9996	.9996	.9997

### P-values for z-tests

- 1. Parameter of interest:  $\mu$  = true average wafer thickness
- **2.** Null hypothesis:  $H_0$ :  $\mu = 245$
- 3. Alternative hypothesis:  $H_a$ :  $\mu \neq 245$
- **4.** Formula for test statistic value:  $z = \frac{\bar{x} 245}{s/\sqrt{n}}$
- 5. Calculation of test statistic value:  $z = \frac{246.18 245}{3.60/\sqrt{50}} = 2.32$
- 6. Determination of P-value: Because the test is two-tailed,

$$P$$
-value =  $2[1 - \Phi(2.32)] = .0204$ 

7. Conclusion: Using a significance level of .01, H<sub>0</sub> would not be rejected since .0204 > .01. At this significance level, there is insufficient evidence to conclude that true average thickness differs from the target value.



## P-values for z-tests

$$P\text{-value:}\quad P = \begin{cases} 1 - \Phi(z) & \text{for an upper-tailed test} \\ \Phi(z) & \text{for a lower-tailed test} \\ 2[1 - \Phi(|z|)] & \text{for a two-tailed test} \end{cases}$$

## P-values for *t*-tests

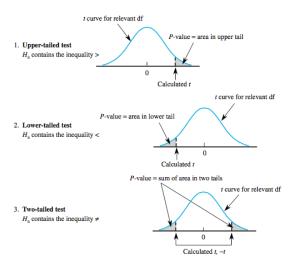


Figure 9.8 P-values for t tests

# Practice problem

#### Problem

Suppose we want to test

$$H_0: \mu = 25$$

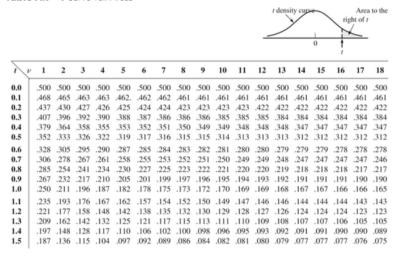
$$H_{\rm a}$$
 :  $\mu > 25$ 

from a sample with n = 5 and the calculated value

$$t = \frac{\bar{x} - 25}{s/\sqrt{n}} = 1.02$$

- (a) What is the P-value of the test
- (b) Should we reject the null hypothesis?

Table A.7 t Curve Tail Areas



# Interpreting P-values

#### A P-value:

- is not the probability that  $H_0$  is true
- is not the probability of rejecting  $H_0$
- is the probability, calculated assuming that  $H_0$  is true, of obtaining a test statistic value at least as contradictory to the null hypothesis as the value that actually resulted

# Example 1

Let  $\mu$  denote the mean reaction time to a certain stimulus. For a large-sample z test of  $H_0$ :  $\mu = 5$  versus  $H_a$ :  $\mu > 5$ , and the P-value associated with each of the given values of the z test statistic.

- **a.** 1.42 **b.** .90 **c.** 1.96
- **d.** 2.48 **e.** -.11

# Example 2

On the label, Pepperidge Farm bagels are said to weigh four ounces each (113 grams). A random sample of six bagels resulted in the following weights (in grams):

117.6 109.5 111.6 109.2 119.1 110.8

**a.** Based on this sample, is there any reason to doubt that the population mean is at least 113 grams?